

## 2<sup>nd</sup> Generation thinQ!<sup>TM</sup> SiC Schottky Diode

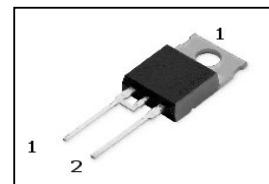
### Features

- Revolutionary semiconductor material - Silicon Carbide
- Switching behavior benchmark
- No reverse recovery/ No forward recovery
- No temperature influence on the switching behavior
- High surge current capability
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Breakdown voltage tested at 5mA<sup>2)</sup>

### Product Summary

$V_{DC}$	600	V
$Q_c$	8	nC
$I_F$	4	A

PG-T0220-2-2



**thinQ! 2G Diode specially designed for fast switching applications like:**

- CCM PFC
- Motor Drives

Type	Package		Marking	Pin 1	Pin 2
IDT04S60C	PG-T0220-2-2		D04S60C	C	A

**Maximum ratings, at  $T_j=25$  °C, unless otherwise specified**

Parameter	Symbol	Conditions	Value	Unit
Continuous forward current	$I_F$	$T_c < 140$ °C	4	A
RMS forward current	$I_{F,RMS}$	$f=50$ Hz	5.6	
Surge non-repetitive forward current, sine halfwave	$I_{F,SM}$	$T_c = 25$ °C, $t_p = 10$ ms	32	
Repetitive peak forward current	$I_{F,RM}$	$T_j = 150$ °C, $T_c = 100$ °C, $D = 0.1$	18	
Non-repetitive peak forward current	$I_{F,max}$	$T_c = 25$ °C, $t_p = 10$ µs	132	
$i^2t$ value	$\int i^2 dt$	$T_c = 25$ °C, $t_p = 10$ ms	5.1	A <sup>2</sup> s
Repetitive peak reverse voltage	$V_{RRM}$		600	V
Diode dv/dt ruggedness	$dv/dt$	$V_R = 0 \dots 480$ V	50	V/ns
Power dissipation	$P_{tot}$	$T_c = 25$ °C	42	W
Operating and storage temperature	$T_j, T_{stg}$		-55 ... 175	°C
Mounting torque		M3 and M3.5 screws	60	Mcm

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Thermal characteristics**

Thermal resistance, junction - case	$R_{thJC}$		-	-	3.6	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	leaded	-	-	62	
Soldering temperature, wavesoldering only allowed at leads	$T_{sold}$	1.6mm (0.063 in.) from case for 10s	-	-	260	°C

**Electrical characteristics**, at  $T_j=25$  °C, unless otherwise specified

**Static characteristics**

DC blocking voltage	$V_{DC}$	$I_R=0.05$ mA	600	-	-	V
Diode forward voltage	$V_F$	$I_F=4$ A, $T_j=25$ °C	-	1.7	1.9	
		$I_F=4$ A, $T_j=150$ °C	-	2	2.4	
Reverse current	$I_R$	$V_R=600$ V, $T_j=25$ °C	-	0.5	50	$\mu$ A
		$V_R=600$ V, $T_j=150$ °C	-	2	500	

**AC characteristics**

Total capacitive charge	$Q_c$	$V_R=400$ V, $I_F \leq I_{F,max}$ , $di_F/dt=200$ A/ $\mu$ s,	-	8	-	nC
Switching time <sup>3)</sup>	$t_c$	$T_j=150$ °C	-	-	<10	ns
	C	$V_R=1$ V, $f=$ MHz	-	130	-	pF
		$V_R=300$ V, $f=1$ MHz	-	20	-	
		$V_R=600$ V, $f=1$ MHz	-	20	-	

<sup>1)</sup> J-STD20 and JESD22

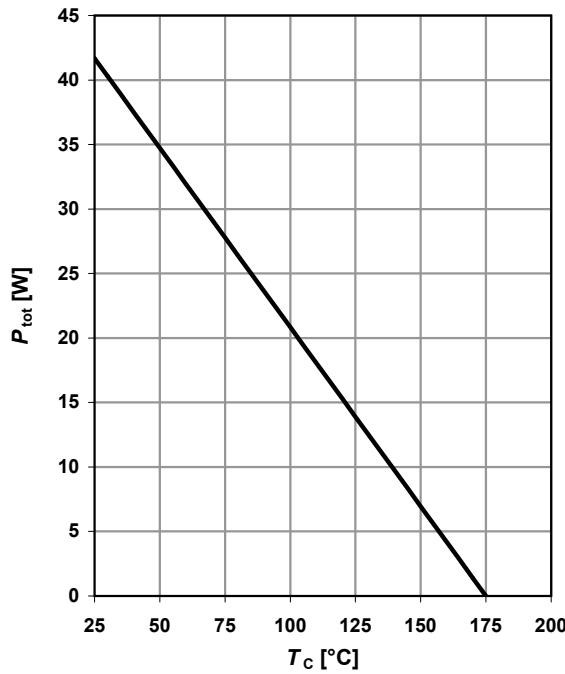
<sup>2)</sup> All devices tested under avalanche conditions, for a time period of 5ms, at 5mA.

<sup>3)</sup>  $t_c$  is the time constant for the capacitive displacement current waveform (independent from  $T_j$ ,  $I_{LOAD}$  and  $di/dt$ ), different from  $t_{rr}$ , which is dependent on  $T_j$ ,  $I_{LOAD}$ ,  $di/dt$ . No reverse recovery time constant  $t_{rr}$  due to absence of minority carrier injection.

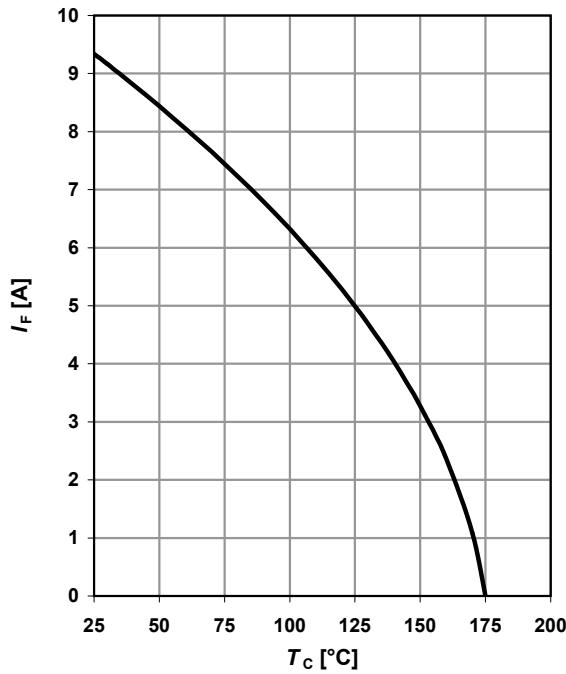
<sup>4)</sup> Only capacitive charge occurring, guaranteed by design.

**1 Power dissipation**

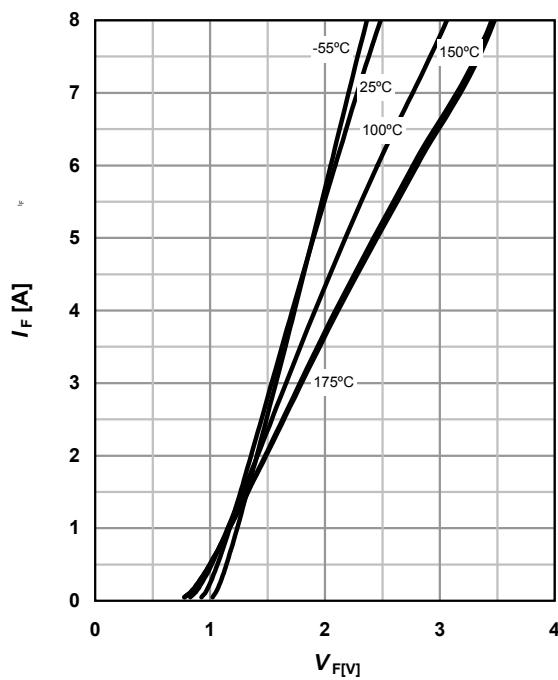
$$P_{\text{tot}} = f(T_c)$$

 parameter:  $R_{\text{thJC(max)}}$ 

**2 Diode forward current**

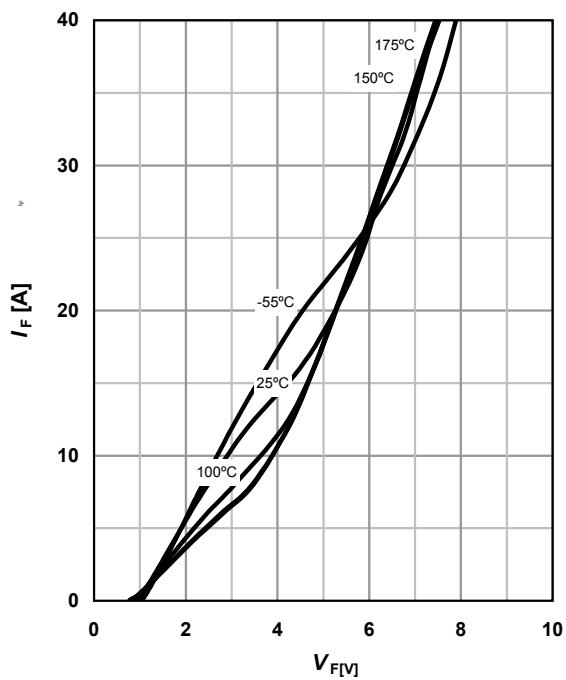
$$I_F = f(T_c); T_j \leq 175^\circ\text{C}$$

 parameter:  $R_{\text{thJC(max)}}; V_{F(\text{max})}$ 

**3 Typ. forward characteristic**

$$I_F = f(V_F); t_p = 400 \mu\text{s}$$

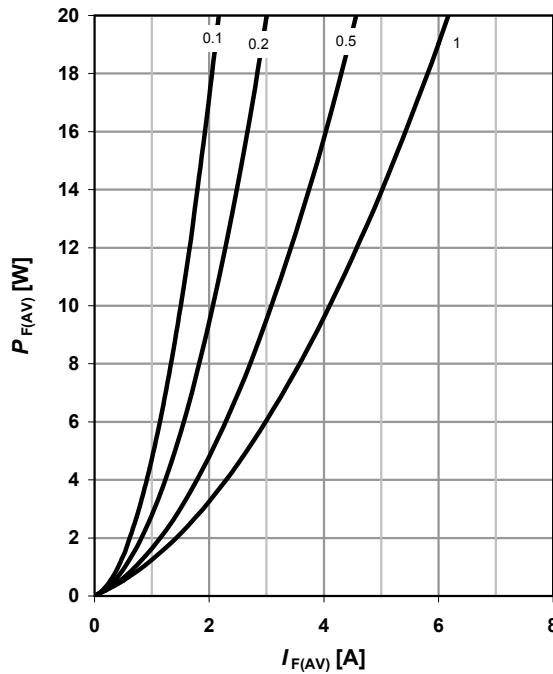
 parameter:  $T_j$ 

**4 Typ. forward characteristic in surge current mode**

$$I_F = f(V_F); t_p = 400 \mu\text{s}; \text{parameter: } T_j$$



**5 Typ. forward power dissipation vs.  
average forward current**

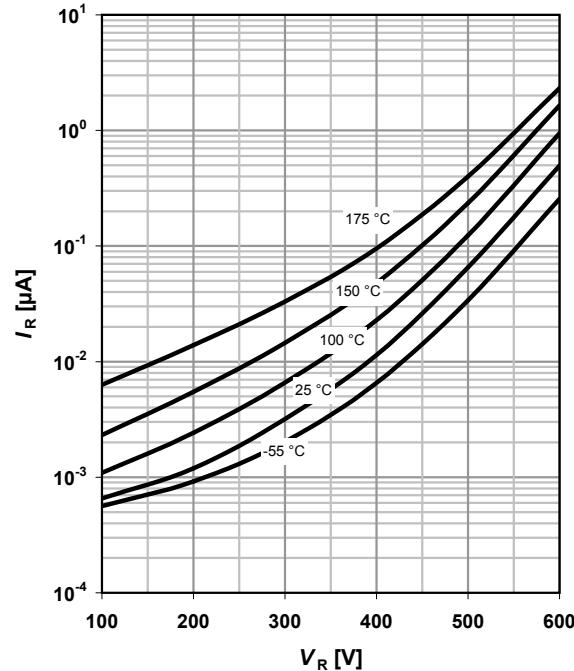
$P_{F,AV}=f(I_F)$ ,  $T_C=100\text{ }^\circ\text{C}$ , parameter:  $D=t_p/T$



**6 Typ. reverse current vs. reverse voltage**

$I_R=f(V_R)$

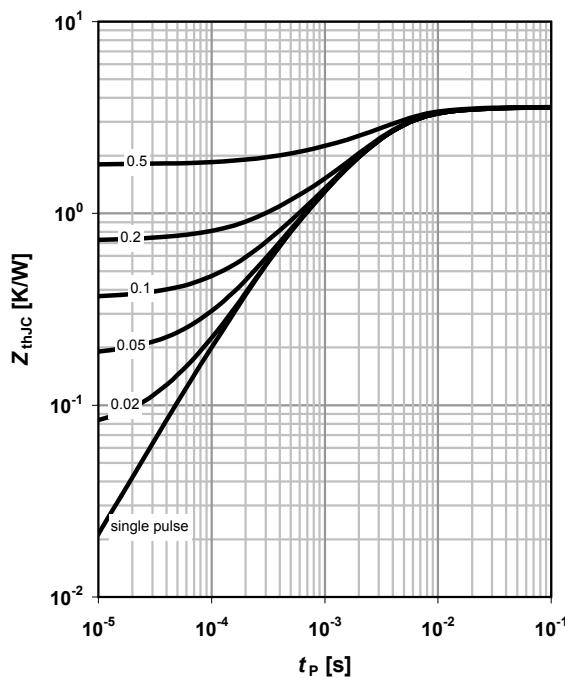
parameter:  $T_j$



**7 Transient thermal impedance**

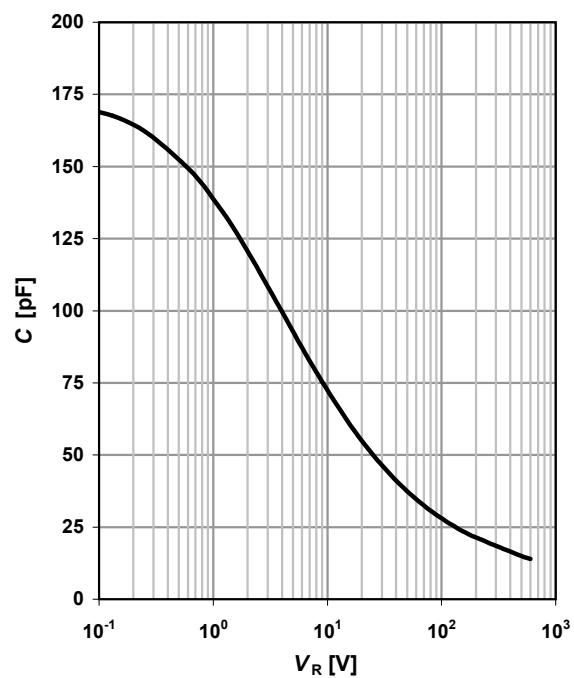
$Z_{thJC}=f(t_p)$

parameter:  $D=t_p/T$



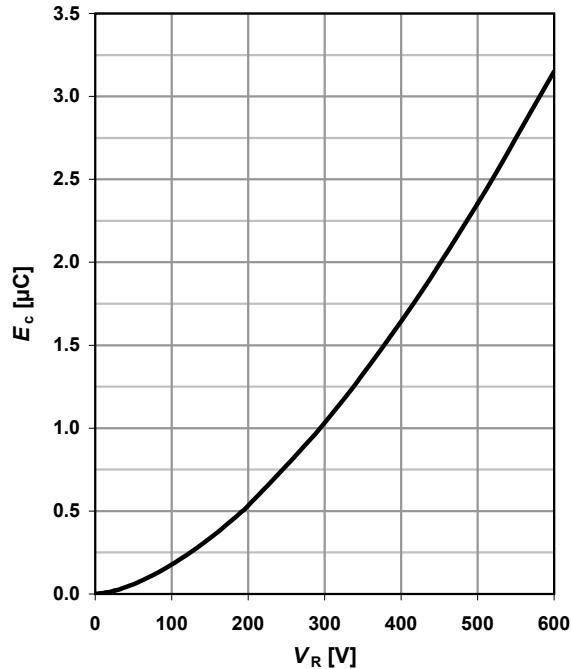
**8 Typ. capacitance vs. reverse voltage**

$C=f(V_R)$ ;  $T_C=25\text{ }^\circ\text{C}$ ,  $f=1\text{ MHz}$

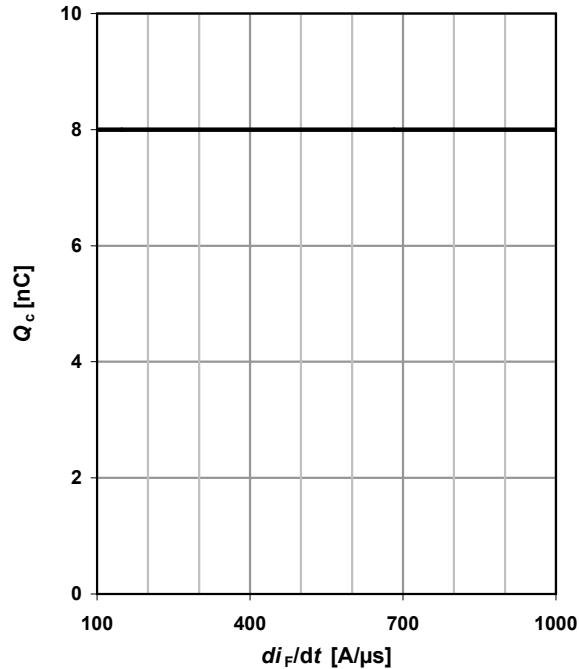


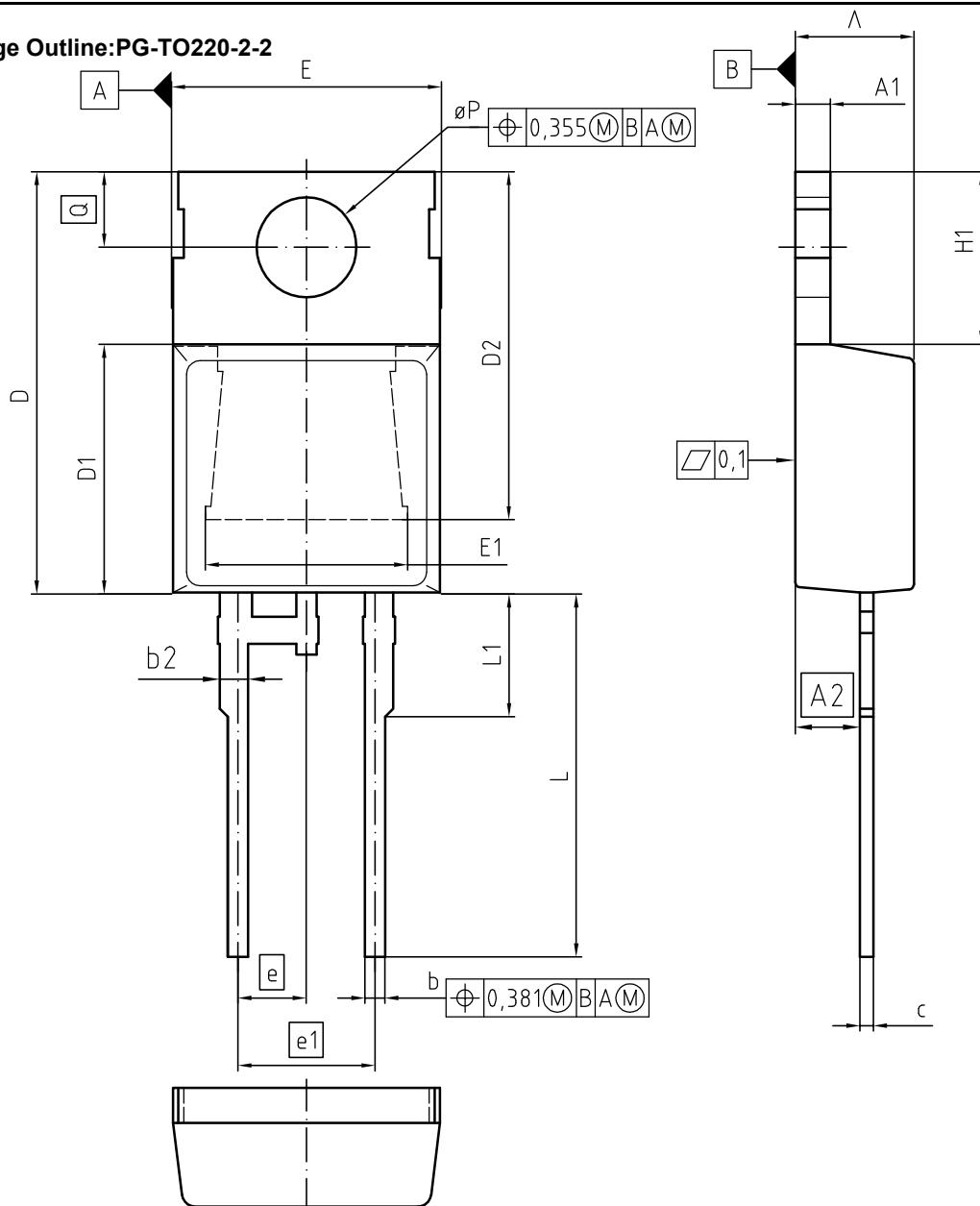
**9 Typ. C stored energy**

$$E_C = f(V_R)$$


**10 Typ. capacitance charge vs. current slope**

$$Q_C = f(di_F/dt)^{4/3}, \quad T_J = 150 \text{ } ^\circ\text{C}; \quad i_F \leq i_{F,\max}$$



**Package Outline:PG-T0220-2-2**


DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.191	4.699	0.165	0.185
A1	1.170	1.400	0.046	0.055
A2	2.215	2.718	0.087	0.107
b	0.635	0.889	0.025	0.035
b2	0.950	1.651	0.037	0.065
c	0.330	0.635	0.013	0.025
D	14.808	15.950	0.583	0.628
D1	8.509	9.450	0.335	0.372
D2	12.850	14.245	0.506	0.561
E	9.677	10.363	0.381	0.408
E1	6.500	8.788	0.256	0.346
e	2.540		0.100	
e1	5.080		0.200	
N	2		2	
H1	5.900	6.900	0.232	0.272
L	12.700	14.000	0.500	0.551
L1	3.048	4.800	0.120	0.189
øP	3.550	3.886	0.140	0.153
Q	2.540	3.048	0.100	0.120

DOCUMENT NO.	Z8B00003320
SCALE	0 2.5 0 2.5 5mm
EUROPEAN PROJECTION	
ISSUE DATE	28-02-2007
REVISION	02



---

**Published by**  
**Infineon Technologies AG**  
**81726 Munich, Germany**  
**© 2008 Infineon Technologies AG**  
**All Rights Reserved.**

### **Legal Disclaimer**

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

### **Information**

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office ([www.infineon.com](http://www.infineon.com)).

### **Warnings**

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office. Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.